

**Search Notes**

Application/Control No.

10/506,497

Examiner

Patrick J. Lee

Applicant(s)/Patent under  
Reexamination

NYGARD, EINAR

Art Unit

2878

**SEARCHED**

Class	Subclass	Date	Examiner
250	208.1, 214.1, 214R	3/8/2006 3/10/2006	PL
438	57-60	3/10/2006	PL
438	64-67	3/10/2006	PL
438	73-81	3/10/2006	PL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted w/ S. Allen AU 2878 CL 250	3/8/2006	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	3/8/2006	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	3/10/2006	PL